

50

Fig. 1B

Fig. 3A

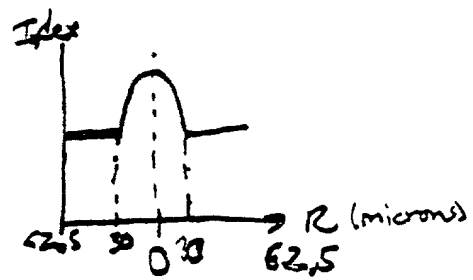


Fig. 3B

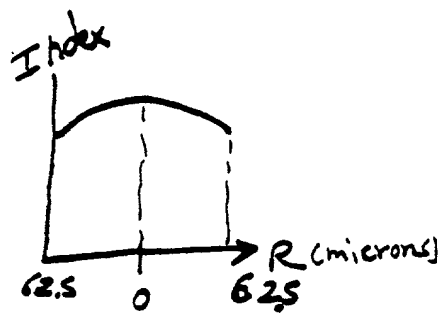


Fig. 4A is a schematic diagram of a laser system for measuring the optical properties of a sample. The system includes a laser source 66, a beam splitter 60, a sample 18, an AOM 70, and a detector 74. The laser source 66 emits a beam that is split by the beam splitter 60. One portion of the beam passes through the sample 18 and is detected by the detector 74. The other portion of the beam is directed to the AOM 70, which is used to modulate the beam. The AOM 70 is driven by a radio frequency (RF) signal 72. The modulated beam is then detected by the detector 74. The detector 74 is connected to a computer 76, which is used to process the data and determine the optical properties of the sample.

Fig. 4A

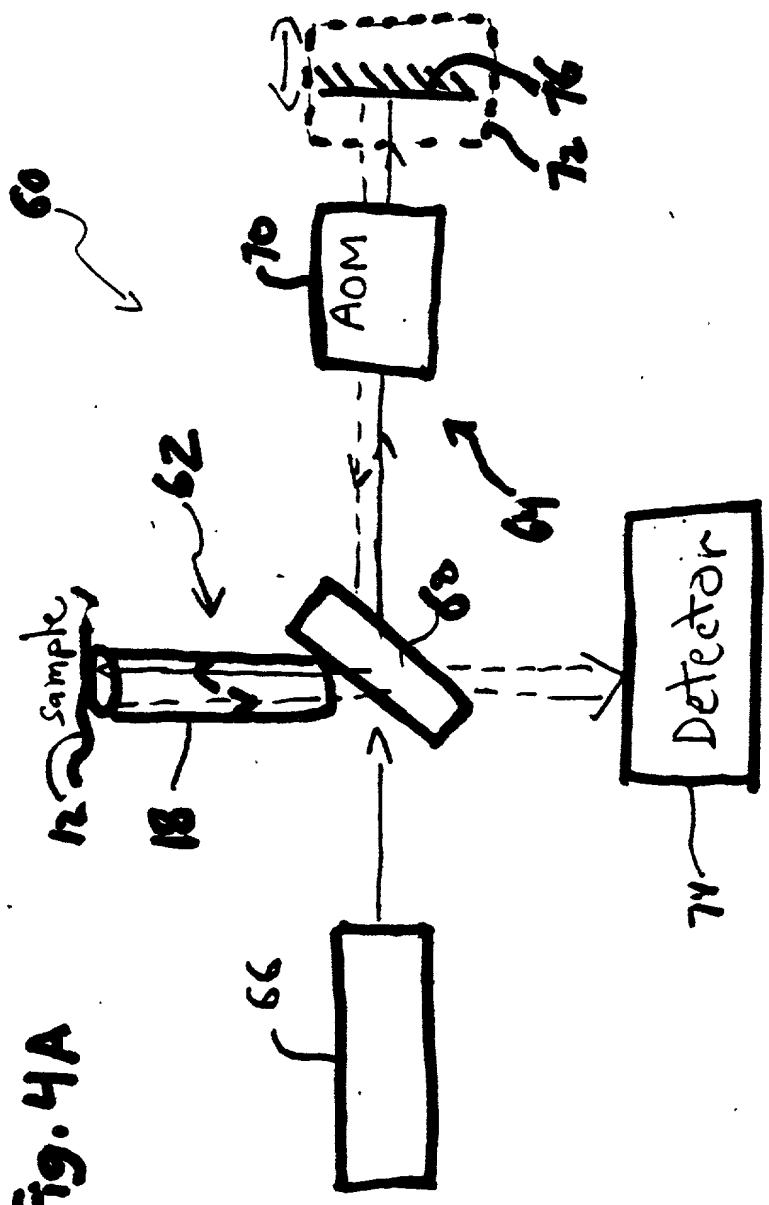


Fig. 4B

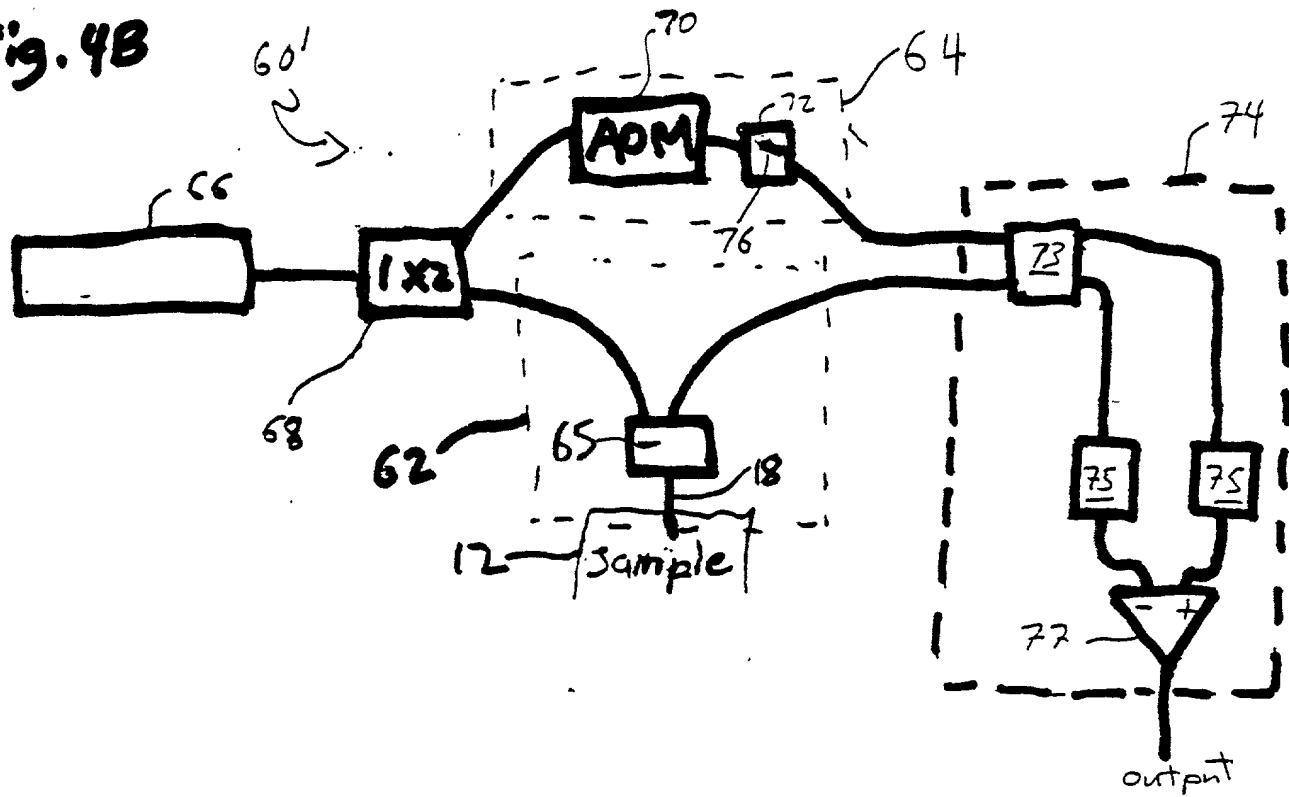


Fig. 4C

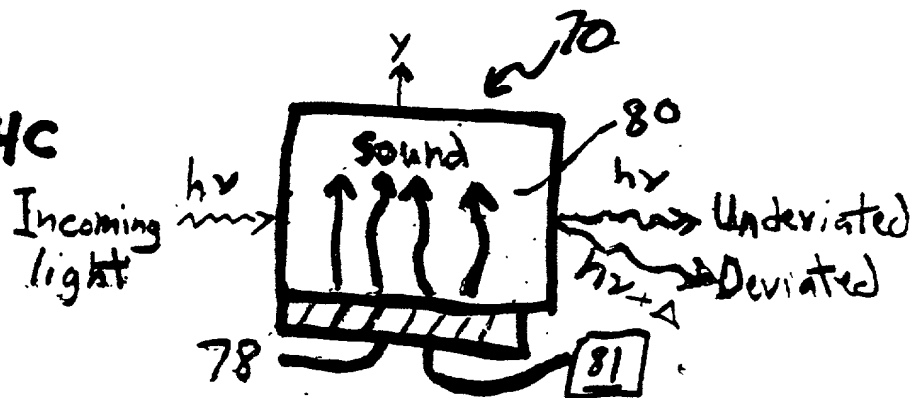


Fig. 5

Fig. 5 is a schematic diagram of a depth scanner and dispersion compensator.

